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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Walter SCHWARZENBACH et al. Confirmation No.: 3337
Application No.: 10/766,207 Group Art Unit: 2822
Filing Date: January 29, 2004 Examiner: Khanh B. Duong
For: METHOD OF DETACHING A LAYER FROM A WAFER USING A LOCALIZED STARTING AREA Attorney Docket No.: 4717-11600

SUBMISSION OF PRIORITY DOCUMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:


Applicants have claimed priority under 35 U.S.C. § 119 of French Application No. 03 09597 filed August 4, 2003. In support of this claim, a certified copy of said application is submitted herewith.

No fee or certification is believed to be due for this submission. Should any fees be required, please charge such fees to Winston & Strawn LLP Deposit Account No. 50-1814.

Respectfully submitted,

11/29/05

Date



Allan A. Fanucci (Reg. No. 30,256)

WINSTON & STRAWN LLP
Customer No. 28765

212-294-3311